

Notice of References Cited		Application/Control No. 10/722,776	Applicant(s)/Patent Under Reexamination WANG ET AL.	
		Examiner NANCY BITAR	Art Unit 2624	Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2005/0278324	12-2005	Fan et al.	707/006
*	B US-7,065,230	06-2006	Yuasa et al.	382/104
*	C US-7,191,175	03-2007	Evans, Lynne Marie	707/5
*	D US-7,139,764	11-2006	Lee, Shih-Jong J.	707/100
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L	US-			
M	US-			

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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V	Brin et al (Near Neighbor Search in Large Metric Spaces, Nov 20, 1995).
W	OP-Cluster: Clustering by Tendency in High Dimensional Space, Jinze Liu and Wei Wan
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.